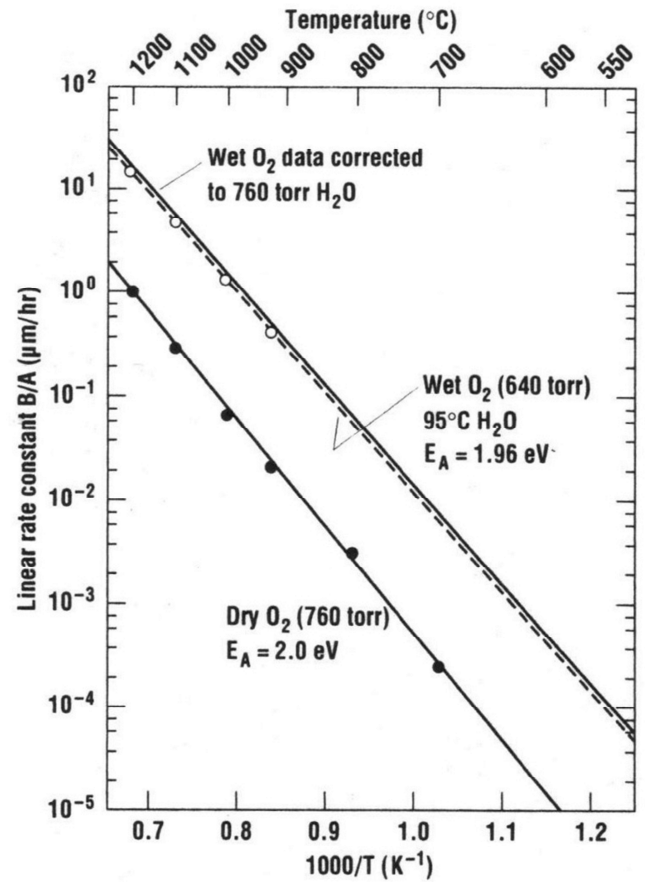


**Figure 4.2** Arrhenius plot of the  $B$  oxidation coefficient. The wet parameters depend on the  $\text{H}_2\text{O}$  concentration and therefore on the gas flows and pyrolysis conditions (after Deal and Grove).



**Figure 4.3** Arrhenius plot of the ratio  $(B/A)$  of the oxidation parameters (after Deal and Grove).

$$\text{Deal-Grove Model: } t_{ox}^2 + At_{ox} = B(t + \tau), \quad \tau = \frac{t_o^2 + At_o}{B}$$

Table and Graphs from S. Campbell, *Fabrication Engineering at the Micro- and Nanoscale*, 3<sup>rd</sup> edition.

**Table 4.1** Oxidation coefficients for silicon - For (111) silicon

Temperature (°C)	Dry			Wet (640 torr)	
	$A$ (μm)	$B$ (μm <sup>2</sup> /hr)	$\tau$ (hr)	$A$ (μm)	$B$ (μm <sup>2</sup> /hr)
800	0.370	0.0011	9	—	—
920	0.235	0.0049	1.4	0.50	0.203
1000	0.165	0.0117	0.37	0.226	0.287
1100	0.090	0.027	0.076	0.11	0.510
1200	0.040	0.045	0.027	0.05	0.720

The  $\tau$  parameter is used to compensate for the rapid growth regime for thin oxides. (After Deal and Grove.)